Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10636044	CHIU ET AL.
Examiner	Art Unit
Augustine, Nicholas	2179

Examiner

SEARCHED

Class	Subclass	Date	Examiner
709	201-205, 214, 231-232	6/5/08	NA
715	748, 751, 753, 761, 863	6/5/08	NA
709	201-205, 214, 231-232	8/21/08	NA
710	1	8/21/08	NA
715	748, 751, 753, 761, 863	8/21/08	NA
709	201-205, 214, 231-232	3/12/2009	NA
710	1	3/12/2009	NA
715	748, 751, 753, 761, 863	3/12/2009	NA
709	201-205, 214, 231-232	8/19/2009	NA
715	748, 751, 753, 761, 863	8/19/2009	NA
715	730,737,748,751,753,761,766,863	2/4/2010	NA
709	201-205, 214, 231-232	2/4/2010	NA
715	730,737,748,751,753,761,766,863	7/17/2010	NA
709	201-205, 214, 231-232	7/17/2010	NA
715	730,737,748,751,753,761,766,863	4/11/2011	NA

SEARCH NOTES

Search NotesDateIUpdated Search06/26/2007NAUpdated East Search: US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO;
DERWENT; IBM_TDB8/21/08NAUpdated East Search: US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO;
USPAT; USOCR; FPRS; EPO; JPO;3/12/2009NA

NA DERWENT; IBM TDB Updated East Search: US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; 8/19/2009 NA DERWENT; IBM_TDB Updated East Search: US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; 2/4/2010 NA DERWENT; IBM_TDB Consulted with Ba Huynh 2/4/2010 NA Updated East Search: US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; 7/17/2010 NA DERWENT; IBM TDB Consulted with Ba Huynh 7/17/2010 NA Updated East Search: US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; NA 4/11/2011 DERWENT; IBM_TDB

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	INTERFERENCE SEARCH		
Class	Subclass	Date	Examiner
715	730,737,748,751,753,761,766,863	2/4/2010	NA
709	201-205, 214, 231-232	2/4/2010	NA
715	730,737,748,751,753,761,766,863	7/17/2010	NA
709	201-205, 214, 231-232	7/17/2010	NA

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